

<b>Notice of References Cited</b>	Application/Control No. 10/585,582		Applicant(s)/Patent Under Reexamination FINKELSTEIN ET AL.	
	Examiner Matthew Reames		Art Unit 2893	Page 1 of 1

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*	B	US-6,333,516	12-2001	Katoh et al.	257/22
*	C	US-5,001,437	03-1991	Miyata et al.	315/501
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al. "spin polarized reflection of electrons in a two-dimensional electron system," <a href="http://xxx.lanl.gov/abs/cond-mat/0308569">http://xxx.lanl.gov/abs/cond-mat/0308569</a> (8/27/2003)
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.